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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 10/820,575
Filing Date April 7, 2004
Inventor Scott E. Moore et al.
Assignee Micron Technology, Inc.
Group Art Unit 2877
Examiner Roy Punnoose
Attorney's Docket No. MI22-2493
Title: Semiconductor Workpiece Processing Methods and Turbidity Monitoring Methods

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References – See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. No admission is made regarding whether all the submitted references are prior art.

Respectfully submitted,

Dated: 11/16/06By: 

James D. Shaurette
Reg. No. 39,833

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Sheet 1 of 1

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2493		SERIAL NO. 10/820,575	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Scott E. Moore et al.			
				FILING DATE April 7, 2004		GROUP 1734	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5,865,665	2/2/1999	Yueh			
	AB	6,207,921	5/4/1993	Vincent, John D.			
	AC	3,809,243	5/7/1974	Teders, Philip J.			
	AD						
	AE						
	AF						
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	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AQ						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
	AR						Yes No
	AS						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER				DATE CONSIDERED			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							